

Dual N-channel 40 V, 9.4 mΩ logic level MOSFET

10 December 2013

Product data sheet

### 1. General description

Dual logic level N-channel MOSFET in an LFPAK56D (Dual Power-SO8) package using TrenchMOS technology. This product has been designed and qualified to AEC Q101 standard for use in high performance automotive applications.

### 2. Features and benefits

- Dual MOSFET
- Q101 Compliant
- Repetitive avalanche rated
- Suitable for thermally demanding environments due to 175 °C rating
- True logic level gate with  $V_{GS(th)}$  rating of greater than 0.5 V at 175 °C

### 3. Applications

- 12 V Automotive systems
- Motors, lamps and solenoid control
- Transmission control
- Ultra high performance power switching

### 4. Quick reference data

Table 1. Qui	ck reference data						
Symbol	Parameter	Conditions		Min	Тур	Max	Unit
V <sub>DS</sub>	drain-source voltage	T <sub>j</sub> ≥ 25 °C; T <sub>j</sub> ≤ 175 °C		-	-	40	V
I <sub>D</sub>	drain current	V <sub>GS</sub> = 5 V; T <sub>mb</sub> = 25 °C; <u>Fig. 1</u>		-	-	30	А
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 °C; <u>Fig. 2</u>		-	-	53	W
Static characte	eristics FET1 and FET2						
R <sub>DSon</sub>	drain-source on-state resistance	V <sub>GS</sub> = 5 V; I <sub>D</sub> = 10 A; T <sub>j</sub> = 25 °C; <u>Fig. 11</u>		-	7.66	9.4	mΩ
Dynamic characteristics FET1 and FET2							
Q <sub>GD</sub>	gate-drain charge	$I_D$ = 10 A; $V_{DS}$ = 32 V; $V_{GS}$ = 5 V; T <sub>j</sub> = 25 °C; Fig. 13; Fig. 14		-	5.3	-	nC





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### 5. Pinning information

Table 2.	Pinning	information		
Pin	Symbol	Description	Simplified outline	Graphic symbol
1	S1	source1	8 7 6 5	D1 D1 D2 D2
2	G1	gate1		
3	S2	source2		
4	G2	gate2		
5	D2	drain2		 S1 G1 S2 G2
6	D2	drain2		mbk725
7	D1	drain1	1 2 3 4 LFPAK56D (SOT1205)	
8	D1	drain1	(0011200)	

## 6. Ordering information

Table 3.   Ordering information							
Type number	Package						
	Name	Description	Version				
BUK9K8R7-40E	LFPAK56D	Plastic single ended surface mounted package (LFPAK56D); 8 leads	SOT1205				

### 7. Marking

Table 4. Marking codes	
Type number	Marking code
BUK9K8R7-40E	98E740

## 8. Limiting values

#### Table 5.Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions		Min	Max	Unit
V <sub>DS</sub>	drain-source voltage	T <sub>j</sub> ≥ 25 °C; T <sub>j</sub> ≤ 175 °C		-	40	V
V <sub>DGR</sub>	drain-gate voltage	R <sub>GS</sub> = 20 kΩ		-	40	V
V <sub>GS</sub>	gate-source voltage	$T_j \le 175 \text{ °C}; \text{ Pulsed}$	[1][2]	-15	15	V
		T <sub>j</sub> ≤ 175 °C; DC		-10	10	V
I <sub>D</sub>	drain current	T <sub>mb</sub> = 25 °C; V <sub>GS</sub> = 5 V; <u>Fig. 1</u>		-	30	А
		T <sub>mb</sub> = 100 °C; V <sub>GS</sub> = 5 V; <u>Fig. 1</u>		-	30	А
I <sub>DM</sub>	peak drain current	$T_{mb}$ = 25 °C; pulsed; $t_p \le 10 \ \mu$ s; Fig. 4		-	211	А
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## **BUK9K8R7-40E**

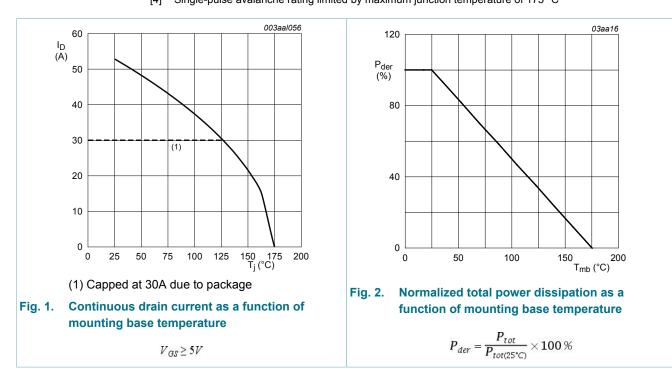
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Symbol	Parameter	Conditions		Min	Max	Unit	
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 °C; <u>Fig. 2</u>		-	53	W	
T <sub>stg</sub>	storage temperature			-55	175	°C	
Tj	junction temperature			-55	175	°C	
Source-drain	n diode FET1 and FET2						
I <sub>S</sub>	source current	T <sub>mb</sub> = 25 °C		-	30	А	
I <sub>SM</sub>	peak source current	pulsed; $t_p \le 10 \ \mu s$ ; $T_{mb} = 25 \ ^\circ C$		-	211	А	
Avalanche Ruggedness FET1 and FET2							
E <sub>DS(AL)S</sub>	non-repetitive drain-source avalanche energy	$I_{D} = 30 \text{ A}; V_{sup} \le 40 \text{ V}; V_{GS} = 10 \text{ V};$ $T_{j(init)} = 25 \text{ °C}; \text{ Fig. 3}$	[3][4]	-	84	mJ	

[1] Accumulated Pulse duration up to 50 hours delivers zero defect ppm

[2] Significantly longer life times are achieved by lowering  $T_i$  and or  $V_{GS}$ .

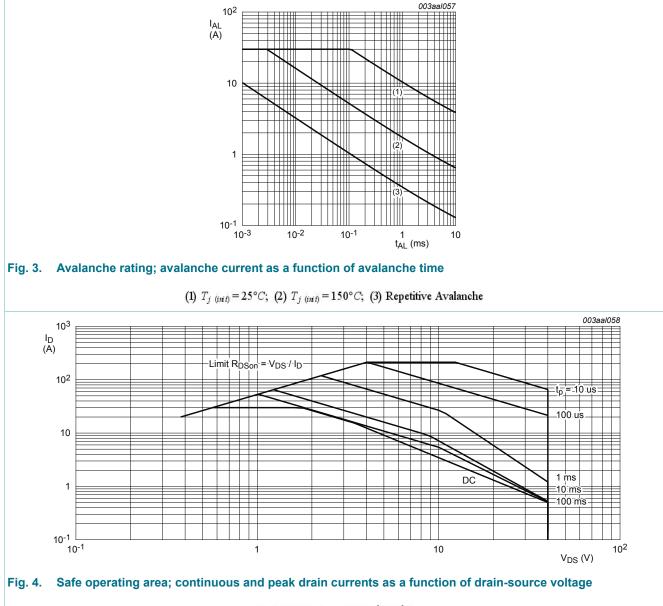
[3] Refer to application note AN10273 for further information



[4] Single-pulse avalanche rating limited by maximum junction temperature of 175 °C

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 $T_{mb} = 25^{\circ}C; \ I_{DM}$  is a single pulse

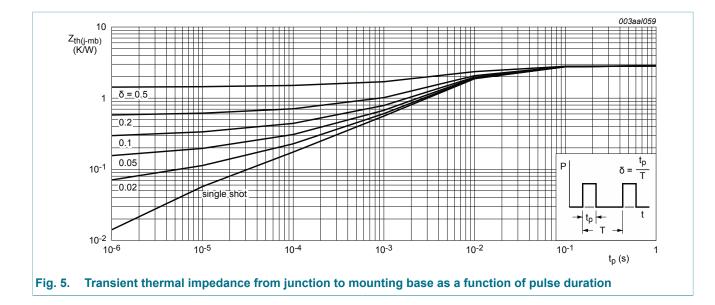
### 9. Thermal characteristics

Table 6. The	rmal characteristics					
Symbol	Parameter	Conditions	Min	Тур	Мах	Unit
R <sub>th(j-mb)</sub>	thermal resistance from junction to mounting base	<u>Fig. 5</u>	-	-	2.84	K/W
R <sub>th(j-a)</sub>	thermal resistance from junction to ambient	Minimum footprint; mounted on a printed circuit board	-	95	-	K/W

#### Table 6. Thermal characteristics

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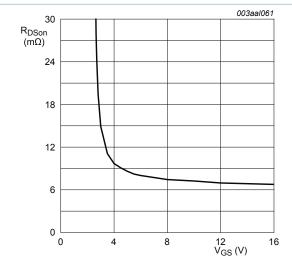
### **10. Characteristics**

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static chara	acteristics FET1 and FET2	· · · · · ·				
V <sub>(BR)DSS</sub>	drain-source	$I_D$ = 250 µA; $V_{GS}$ = 0 V; $T_j$ = -55 °C	36	-	-	V
	breakdown voltage	I <sub>D</sub> = 250 μA; V <sub>GS</sub> = 0 V; T <sub>j</sub> = 25 °C	40	-		V
V <sub>GS(th)</sub>	gate-source threshold voltage	I <sub>D</sub> = 1 mA; V <sub>DS</sub> = V <sub>GS</sub> ; T <sub>j</sub> = 25 °C; Fig. 9; Fig. 10	1.4	1.7	2.1	V
		I <sub>D</sub> = 1 mA; V <sub>DS</sub> = V <sub>GS</sub> ; T <sub>j</sub> = 175 °C; Fig. 9; Fig. 10	0.5	-	-	V
	I <sub>D</sub> = 1 mA; V <sub>DS</sub> = V <sub>GS</sub> ; T <sub>j</sub> = -55 °C; Fig. 9; Fig. 10	-	-	2.45	V	
I <sub>DSS</sub>	drain leakage current	V <sub>DS</sub> = 40 V; V <sub>GS</sub> = 0 V; T <sub>j</sub> = 175 °C	-	-	500	μA
		$V_{DS}$ = 40 V; $V_{GS}$ = 0 V; $T_j$ = 25 °C	-	0.02	1	μA
I <sub>GSS</sub>	gate leakage current	$V_{GS}$ = -10 V; $V_{DS}$ = 0 V; $T_j$ = 25 °C	- 2 100	100	nA	
		$V_{GS}$ = 10 V; $V_{DS}$ = 0 V; $T_j$ = 25 °C	-	- -   1.7 2.1   1.7 2.1   - -   - -   - 2.45   - 500   0.02 1   2 100   2 100   7.66 9.4   15.4 18.9   6.26 8	nA	
R <sub>DSon</sub>	drain-source on-state	V <sub>GS</sub> = 5 V; I <sub>D</sub> = 10 A; T <sub>j</sub> = 25 °C; <u>Fig. 11</u>	-	-   0.02   1     -   2   100     -   2   100	mΩ	
	resistance	V <sub>GS</sub> = 5 V; I <sub>D</sub> = 10 A; T <sub>j</sub> = 175 °C; Fig. 11; Fig. 12	-	15.4	18.9	mΩ
		V <sub>GS</sub> = 10 V; I <sub>D</sub> = 10 A; T <sub>j</sub> = 25 °C; Fig. 11	-	6.26	8	mΩ
Dynamic ch	naracteristics FET1 and FE	T2	1	1		
Q <sub>G(tot)</sub>	total gate charge	$I_D$ = 10 A; $V_{DS}$ = 32 V; $V_{GS}$ = 5 V;	-	15.7	-	nC
Q <sub>GS</sub>	gate-source charge	T <sub>j</sub> = 25 °C; <u>Fig. 13; Fig. 14</u>	-	3.2	-	nC

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Symbol	Parameter	Conditions	Min	Тур	Мах	Unit
Q <sub>GD</sub>	gate-drain charge		-	5.3	-	nC
C <sub>iss</sub>	input capacitance	$V_{GS}$ = 0 V; $V_{DS}$ = 25 V; f = 1 MHz;	-	1583	2110	pF
C <sub>oss</sub>	output capacitance	T <sub>j</sub> = 25 °C; <u>Fig. 15</u>	-	225	270	pF
C <sub>rss</sub>	reverse transfer capacitance	$V_{DS}$ = 32 V; R <sub>L</sub> = 3.3 Ω; V <sub>GS</sub> = 5 V; R <sub>G(ext)</sub> = 5 Ω; T <sub>j</sub> = 25 °C; I <sub>D</sub> = 10 A	-	114	157	pF
t <sub>d(on)</sub>	turn-on delay time		-	10.8	-	ns
t <sub>r</sub>	rise time		-	19.8	-	ns
t <sub>d(off)</sub>	turn-off delay time		-	20.5	-	ns
t <sub>f</sub>	fall time	-	-	18.2	-	ns
Source-dra	in diode FET1 and FET2					
V <sub>SD</sub>	source-drain voltage	$I_{S}$ = 10 A; $V_{GS}$ = 0 V; $T_{j}$ = 25 °C; <u>Fig. 16</u>	-	0.78	1.2	V
t <sub>rr</sub>	reverse recovery time	$I_{S}$ = 10 A; dI_{S}/dt = -100 A/µs; V <sub>GS</sub> = 0 V;	-	20.5	-	ns
Qr	recovered charge	V <sub>DS</sub> = 20 V; T <sub>j</sub> = 25 °C	-	12.1	-	nC





 $T_j = 25^{\circ}C; \ I_D = 10A$ 

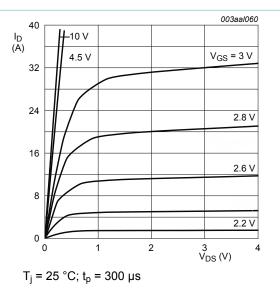
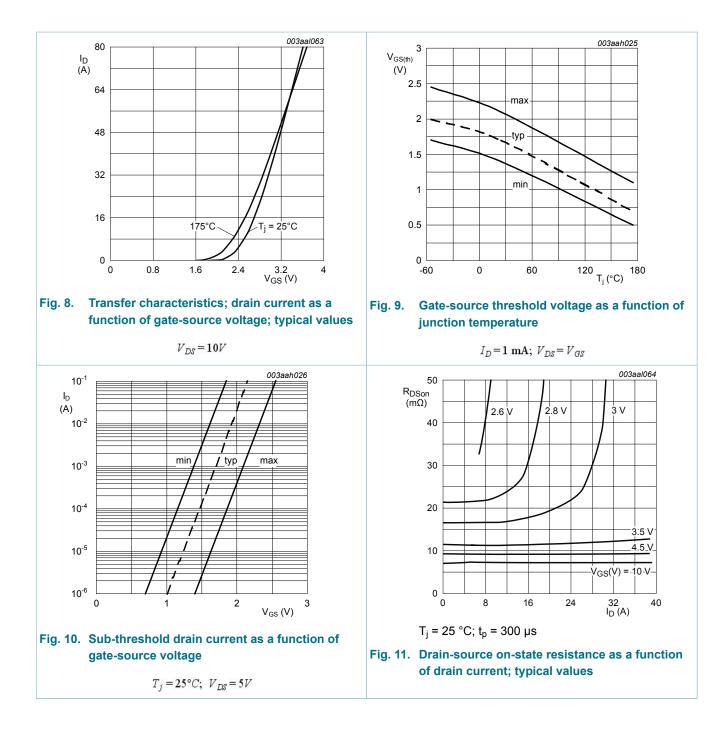


Fig. 7. Output characteristics; drain current as a function of drain-source voltage; typical values

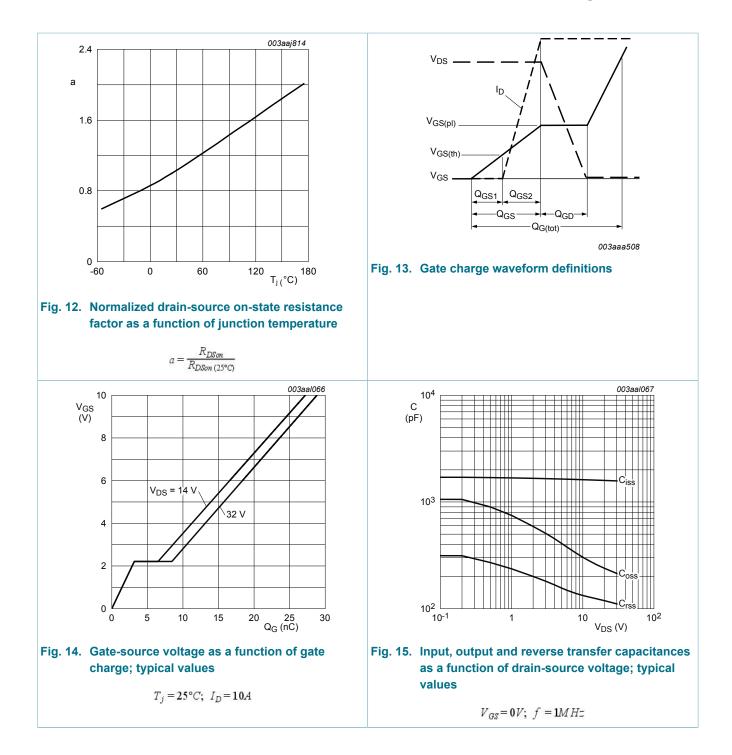
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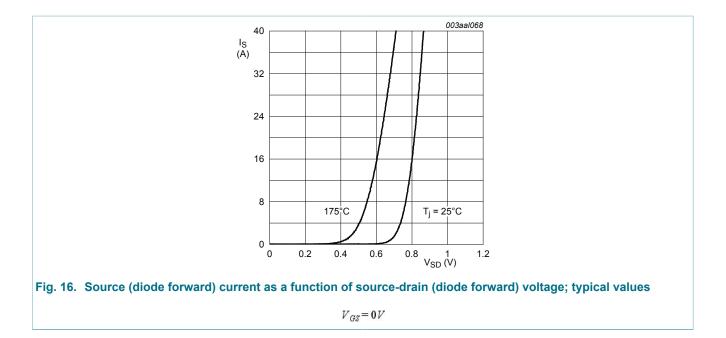
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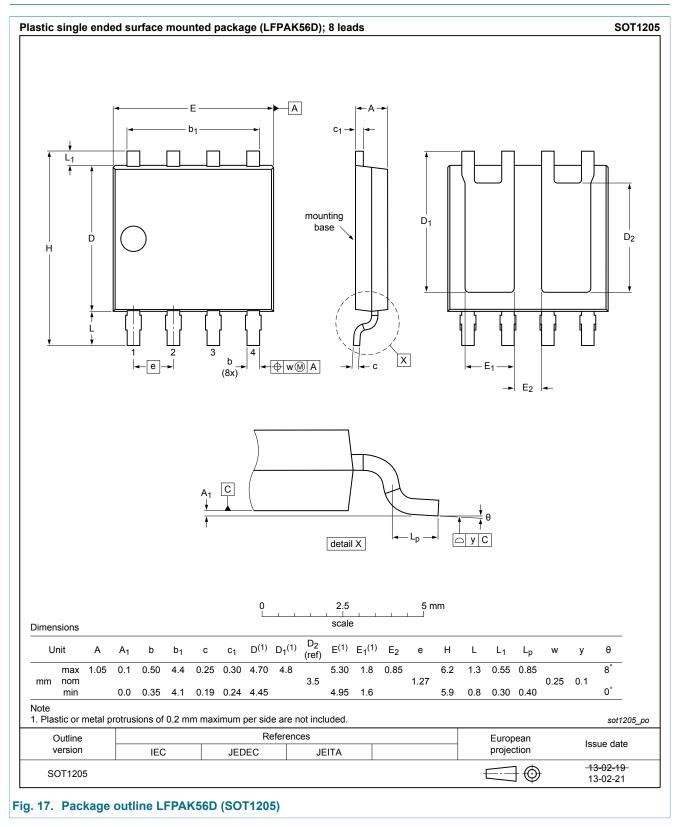
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### 11. Package outline



BUK9K8R7-40E

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Product data sheet

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#### Dual N-channel 40 V, 9.4 mΩ logic level MOSFET

### 12. Legal information

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Document status [1][2]	Product status [ <u>3]</u>	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
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